

## ST92F120/F124/150/F250 TESTFLASH

### INTRODUCTION

The testflash is a ST reserved flash area that contains device information, flash parameters and the boot code. This boot code contains the protocol for In-System Programming and the routines for E3<sup>TM</sup> initialization and management. The testflash is programmed by ST at the factory before shipping and cannot be erased or programmed in user mode.

The purpose of this document is to give an sufficiently accurate description of the testflash content to allow the user to access to the different parameters and routines included in the testflash.

After an overview of the testflash content, the document describes the different routines that can be called at any time by the user code. The last part of this document provides guidelines on the way to handle an E3<sup>TM</sup> failure.

### 1 GLOSSARY AND ACRONYMS

The terms, abbreviations and acronyms used in this document are listed below and described in alphabetical order.

- CONFxR: CONFIguration x Register
- NVAPR: Non Volatile Access Protection Register
- NVCSSx: NV Complementary Sector Status x
- NVESPx: NV Emulation Status Pointer x
- NVPWDx: Non Volatile PassWorD x
- NVWPR: Non Volatile Write Protection Register
- REDxR: REDundancy x Register
- VCSSx: Volatile Complementary Sector Status x
- VESPx: Volatile Emulation Status Pointer x

---

# Table of Contents

---

<b>INTRODUCTION</b> .....	<b>1</b>
<b>1 GLOSSARY AND ACRONYMS</b> .....	<b>1</b>
<b>2 OVERVIEW</b> .....	<b>3</b>
<b>2.1 VECTOR TABLE</b> .....	<b>4</b>
2.1.1 Device identifier .....	4
2.1.2 Testflash code revision .....	4
<b>2.2 USER OTP AREA</b> .....	<b>4</b>
<b>2.3 PROTECTIONS</b> .....	<b>5</b>
<b>3 ROUTINES DESCRIPTION</b> .....	<b>6</b>
<b>3.1 POWER-ON ROUTINE (230020H)</b> .....	<b>6</b>
<b>3.2 NON MASKABLE INTERRUPT ROUTINE</b> .....	<b>7</b>
<b>3.3 CODE UPDATE ROUTINE: IN-SYSTEM PROGRAMMING</b> .....	<b>7</b>
<b>E3™ INITIALIZATION ROUTINE (230026H)</b> .....	<b>9</b>
<b>E3™ SWAP ERROR ROUTINES</b> .....	<b>11</b>
3.5.1 Find Wrong Pages (230029h) .....	11
3.5.2 Find Wrong Bytes (23002Ch) .....	12
3.5.3 Complete Aborted Swap (23002Fh) .....	13
<b>E3™ RESET TO DELIVERY STATUS (230032H)</b> .....	<b>13</b>
<b>3.7 USER ROUTINE FOR EXTERNAL WATCHDOG REFRESH</b> .....	<b>14</b>
<b>4 E3™ FAILURE RECOVERY</b> .....	<b>17</b>
<b>4.1 ERASE OR WRITE ERROR: FATAL ERROR</b> .....	<b>17</b>
<b>4.2 SWAP ERROR: NON FATAL ERROR</b> .....	<b>17</b>
4.2.1 Generate a reset .....	17
4.2.2 Call the “complete aborted swap phase” routine in testflash. ....	17

## 2 OVERVIEW

The structure of the TestFlash content is shown by the following figure:

**Figure 1. ST9 TestFlash content**

230000h	Vector Table
230020h	Power-On routine
230023h	
	Code Update routine (in-system programming)
	SCI Interrupt routines
230026h	E3™ Initialization
	E3™ Management routines
230029h	E3™ Swap Error: Find Wrong Pages
23002Ch	E3™ Swap Error: Find Wrong Bytes in given Page
23002Fh	E3™ Swap Error: Complete aborted Swap phase
230032h	E3™ Reset to delivery status
230035h	
230E80h	Not Used (4 Kbytes)
231E80h	Reserved for Testing (248 bytes)
231F78h	
231F80h	Otp area 124 bytes
231FFCh	Protections

## 2.1 VECTOR TABLE

The first 16 words of the TestFlash contain the Vector Table.

The Power-On Vector is read when exiting from Reset. The Monitor Vector is read in Embedded Emulation Mode after an ETRAP instruction or an external Break. The NMI Vector is read if a Non Maskable Interrupt occurs. The SCI Interrupt Vectors are used for the In-System Programming routine.

**Figure 2. Vector Table**

<b>Vector Table</b>	
230000h	Power-On Vector
230002h	Monitor Vector
230004h	NMI Vector
230006h	Mask Set Number
230008h	Device Identifier
23000Ah	TestFlash Code Revision
230010h	SCI Error Vector
230012h	SCI Address Match Vector
230014h	SCI Receiving End Vector
230016h	SCI Transmitting End Vector

### 2.1.1 Device identifier

This identifier contains the information about the device, its flash size and its reset vector location.

### 2.1.2 Testflash code revision

The CheckSum is the sum of all the bytes from 230000h to 230E77h, it can be used to verify if the actual TestFlash content is the most recent one, or if the TestFlash content is corrupted.

Device	Flash size	Device ID (230008h)	rev 2.6		rev 2.7		rev 2.7.1	
			TF rev (23000 Ah)	Testflash checksum	TF rev (23000 Ah)	Testflash checksum	TF rev (23000 Ah)	Testflash checksum
ST92F124/F150	64K	1024h	xx26h	933BFh	xx27h	8FC55h	0127h	1A7263h
ST92F124/F150	128K	1080h	xx26h	9341Bh	xx27h	8FCB1h	0127h	8FC47h
ST92F250	256K	1100h	xx26h	9339Ch	xx27h	8FC32h	0127h	1A7240h

## 2.2 USER OTP AREA

The 124 bytes of TestFlash from 231F80h to 231FFBh are available to the User application as One Time Programmable area (not erasable).

## 2.3 PROTECTIONS

The TestFlash locations shown by the following figure have a special meaning related to the Access and Write Flash Protection features (refer to the datasheets).

**Figure 3. Protection Map**

Protection	
231FFCh	NVAPR
231FFDh	NVWPR
231FFEh	NVPWD0
231FFFh	NVPWD1

### 3 ROUTINES DESCRIPTION

#### 3.1 POWER-ON ROUTINE (230020H)

**Inputs:** None.

**Outputs:** R0, R1.

**Variables:** R2-R47, R160-R223 (for Stack).

**Goal:** to perform the initializations of ST9 device (Boot Code).

The Power-On routine is executed automatically when exiting reset.

The Power-On routine performs the following operations:

- initialize the Stack Pointer in the Register File (for this reason, this routine modifies the Registers of group A, B, C and D).
- call the “E3™ Initialization routine“ (230026h).
- initialize the MMU paged registers as shown by the following table.

**Table 1. MMU Registers Initialization**

Register	Value	Seg	Notes
DPR0 - R240	00h	0h	1st 16k-page
DPR1 - R241	01h	0h	2nd 16k-page
DPR2 - R242	02h	0h	3rd 16k-page
DPR3 - R243	80h	20h	1st 16k-page
ISR - R248	00h	0h	
DMA SR - R249	20h	20h	
MPSR - R250	21h	21h	
MDPR0 - R251	84h	21h	1st 32k-page
MDPR1 - R252	86h	21h	2nd 32k-page

- Set bit MEMSEL (bit 4) in the R246 (EMR2) register page 21
- Set the Register Page Pointer to page 0.
- Set Group 0 as working registers.
- Set Program Memory.
- read in 000000h the first word of segment 0h (Flash Memory), that is interpreted as the Power-On Vector of the User application. (Warning: if the device identifier is equal to 0080h, the User Reset Vector is read in 01E000h instead of in 000000h).
- check the value of the SOUT0 pin (SOUT pin of SCI0 macrocell): if it is low, the “Code Update routine” is called.

- check the Power-On Vector of the User application: if its value is FFFFh HALT instruction is executed, otherwise the execution jumps into the location it points to.

The User Application should check the 2 Output variables of the Power-On routine:

The “E3<sup>TM</sup> Initialization routine” writes an output code in the R0 register to show if the initialization has been successful (Good Code: A4h), or if the E3<sup>TM</sup> NV Pointers are completely corrupted (Bad Code: 50h) and the user software has to call the “E3<sup>TM</sup> Reset routine” (230032h).

The “Code Update routine” writes an output code in the R1 register to show if no update has been requested or the update has been requested and the SCI communications have been performed correctly (Good Code: 23h), or if the update has been requested, but the SCI communications has not been performed correctly in the timeout of 10ms (for a Fosc frequency of 4MHz) (Bad Code: 3Fh).

Due to the “E3<sup>TM</sup> Initialization routine”, the Power-On routine can last a long time. The typical duration of the Power-On routine as a function of the external clock period Tck is shown in the following table.

**Table 2. Power-On routine typical duration**

Condition	Typical Power-on routine duration with Fosc=4MHz
Normal operation (no E3 <sup>TM</sup> operation)	33 ms
SOUT0 pulled low, no code update	42 ms
Aborted E3 <sup>TM</sup> write operation (worst case)	165 ms (1)

(1) This duration depends also on E3 erasing and programming times

### 3.2 NON MASKABLE INTERRUPT ROUTINE

**Inputs:** None.

**Outputs:** None.

**Variables:** None.

**Goal:** react to a Non Maskable Interrupt when the Vector Table is remapped in TestFlash.

This routine should never be called, since the Vector Table is normally mapped in the Flash address space.

This routine does not perform any operation, simply returns from interrupt.

### 3.3 CODE UPDATE ROUTINE: IN-SYSTEM PROGRAMMING

**Inputs:** None.

**Outputs:** R1.

**Variables:** R4-R15, R208-R223 (for Stack).

**Goal:** in-system programming of the Flash memory content.

The Code Update routine is automatically called by the Power-On routine if the SOUT0 pad is checked low.

The Code Update routine performs the following operations:

- enable the SCI0 peripheral in synchronous mode;
- transmit a synchronisation datum (25h);
- wait for an address match (23h) with a timeout of 10ms (with an Fosc frequency of 4MHz).;
- if the match is not received before the timeout, the execution returns to the Power-On routine with an Error Code in the output register R1 (25h);
- if the match is received, the SCI0 transmits a new datum (21h) to tell the external device that it is ready to receive the data to be loaded in RAM (that represents the code of the in-system programming routine);
- receive two data bytes representing the number of bytes to be loaded (max 4Kbyte);
- receive the specified number of bytes (each one preceded by the transmission of a Ready to Receive character: 21h) and write them in internal RAM starting from address 200010h; the first 4 words should be the interrupt vectors of the 4 possible SCI interrupts, to be used by the in-system programming routine.
- transmit a last datum (21h) as an end of communication request;
- receive the end of communication confirmation datum (any byte other than 25h);
- Reset all the unused Ram locations to FFh;
- Call the address 200018h in internal RAM.
- After completion of the in-system programming routine, an HALT instruction is executed and a Hardware Reset is needed.

The Code Update routine initializes the SCI0 peripheral as shown in the following table:

**Table 3. SCI0 Registers (page 24) initialization**

Register	Value	Notes
IVR - R244	10h	Vector Table in 0010h
ACR - R245	23h	Address Match is 23h
IDPR - R249	00h	SCI interrupt priority is 0
CHCR - R250	83h	8 Data Bits



**Table 3. SCI0 Registers (page 24) initialization**

Register	Value	Notes
CCR - R251	E8h	rec. clock: ext RXCLK0 trx clock: int CLKOUT0
BRGHR - R252	00h	
BRGLR - R253	04h	Baud Rate Divider is 4
SICR - R254	83h	Synchronous Mode
SOCR - R255	01h	

The Code Update routine also remaps the interrupts in TestFlash (ISR = 23h), and configures pins 3 (SOUT0) and 4 (CLKOUT0) of Port 5 as Alternate Function.

The Code Update routine uses 4 Interrupt routines: SCI Receiver Error Interrupt routine (vector in 0010h), SCI Address Match Interrupt routine (vector in 0012h), SCI Receiver Data Ready Interrupt routine (vector in 0014h), SCI Transmitter Buffer Empty Interrupt routine (vector in 0016h).

### 3.4 E3™ INITIALIZATION ROUTINE (230026H)

**Inputs:** None.

**Outputs:** R0.

**Variables:** R1-R47, R160-R223 (for Stack).

**Goal:** to initialize the E3™ Hardware Emulation.

This routine is automatically called by the Power-On routine, but it can be also called by any other routine through a far call:

```
CALLS 23h, 0026h ;E3™ Init
```

The E3™ Initialization routine performs the following operations:

- read the NVCSS1 registers of sector E0 (229003h) and E1 (22D003h);
- if the values of the two NVCSS1 registers are not coherent, the routine returns with the Error Code 50h, without completing the E3™ Initialization;
- if an aborted erase phase is detected, a Sector Erase operation is performed on the bad sector;
- write the VCSS1 register (222003h) with the sector number currently mapping the E3™ data;
- read the NVCSS0 registers of sector E0 (229001h) and E1 (22D001h);
- if the values of the two NVCSS0 registers are not invalid, the routine returns with the Error Code 50h, without completing the E3™ Initialization;

- if an aborted erase phase is detected, a Sector Erase operation is performed on the bad sector;
- write the VCSS0 register (222001h) with the number of the last completed Erase Phase on complementary sector;
- read the NVESP0-63 registers of sector E0 (229000h-22907Eh) and E1 (22D000h-22D07E);
- if the values of a pair of NVESPX registers are invalid, the routine returns with the Error Code 50h, without completing the E3™ Initialization;
- if an aborted swap phase is detected, the swap is completed and a Sector Erase operation is performed on the old sector;
- write each of the VESP0-63 registers (222000h-2223F0h) with the block number in which the relative page is mapped;
- each time an E3™ write operation is performed, a User routine is called to refresh an external Watchdog if needed. [3.7 User routine for External Watchdog Refresh](#) for details.

The User Application should check the Output variable of the E3™ Initialization routine:

Register R0 shows if the E3™ initialization has been possible (Good Code: A4h), or if the E3™ NV Pointers are invalid and the initialization has not been completed (Bad Code: 50h).

In case of an initialization error, the E3™ NV pointers can be reset to a valid content through a far call to the “E3™ Reset routine” (230032h):

```
CALLS 23h, 0032h ;E3™ Reset
```

Note that in this case, any data present in the E3™ is lost.

### 3.5 E3™ SWAP ERROR ROUTINES

#### 3.5.1 Find Wrong Pages (230029h)

**Inputs:** None.

**Outputs:** R16-R23.

**Variables:** R192-R223 (for Stack).

**Goal:** to find the pages in which some new data are different from the old ones after a Swap fail.

This routine has to be called by the User application if bits FEERR of FESR0 (224002h) register and SWER of FESR1 (224003h) register are set after an E3™ write operation. It can be called through a far call:

```
CALLS 23h, 0029h ;Find Wrong Pages
```

This routine performs the following operations:

- initialize a Page counter (from 00h to 3Fh);
- read the 16 bytes of the current Page in the new block (new data after Swap);
- read the 16 bytes of the current Page in the old block (old data before Swap);
- if at least one of the new and old data differs, set the output flag corresponding to the current Page;
- increment the Page counter and repeat the 3 preceding steps, until the last Page is reached;

The User Application should check the 8 Output variables, which are explained in the following table:

**Table 4. Wrong Pages Output Meaning**

Reg	Bit	0 Meaning	1 Meaning
R16	0	Page 00h OK	Page 00h Wrong
R16	X	Pg 00h+X OK	Pg 00h+X Wrong
R16	7	Page 07h OK	Page 07h Wrong
R17	0	Page 08h OK	Page 08h Wrong
R17	X	Pg 08h+X OK	Pg 08h+X Wrong
R17	7	Page 0Fh OK	Page 0Fh Wrong
R18	X	Pg 10h+X OK	Pg 10h+X Wrong
R19	X	Pg 18h+X OK	Pg 18h+X Wrong
R20	X	Pg 20h+X OK	Pg 20h+X Wrong
R21	X	Pg 28h+X OK	Pg 28h+X Wrong

**Table 4. Wrong Pages Output Meaning**

Reg	Bit	0 Meaning	1 Meaning
R22	0	Page 30h OK	Page 30h Wrong
R22	X	Pg 30h+X OK	Pg 30h+X Wrong
R22	7	Page 37h OK	Page 37h Wrong
R23	0	Page 38h OK	Page 38h Wrong
R23	X	Pg 38h+X OK	Pg 38h+X Wrong
R23	7	Page 3Fh OK	Page 3Fh Wrong

**3.5.2 Find Wrong Bytes (23002Ch)****Inputs:** R2-R3.**Outputs:** R0-R1.**Variables:** R192-R223 (for Stack).**Goal:** to find in the specified page the bytes different from the old ones after a Swap fail.

This routine has to be called by the User application if bits FEERR of FESR0 (224002h) register and SWER of FESR1 (224003h) register are set after an E3<sup>TM</sup> write operation. After having executed the "Find Wrong Pages routine", this routine can be called through a far call, providing as input in RR2 the address of the first byte of the Page to check:

```
LDW   RR2, #01C0h;If Page 1Ch is wrong
CALLS 23h, 002Ch ;Find Wrong Bytes
```

This routine performs the following operations:

- initialize a Byte counter (from 0h to Fh);
- read the current Byte in the new block (new data after Swap);
- read the current Byte in the old block (old data before Swap);
- if the new and old data differs, set the output flag corresponding to the current Byte;
- increment the Byte counter and repeat the 3 preceding steps, until the last Byte is reached;

The User Application should check the 2 Output variables, which are explained in the following table:

**Table 5. Wrong Bytes Output Meaning**

Reg	Bit	0 Meaning	1 Meaning
R1	0	Byte 0h OK	Byte 0h Wrong
R1	X	Byte 0h+X OK	Byte 0h+X Wrong
R1	7	Byte 7h OK	Byte 7h Wrong
R0	0	Byte 8h OK	Byte 8h Wrong

**Table 5. Wrong Bytes Output Meaning**

Reg	Bit	0 Meaning	1 Meaning
R0	X	Byte 8h+X OK	Byte 8h+X Wrong
R0	7	Byte Fh OK	Byte Fh Wrong

**3.5.3 Complete Aborted Swap (23002Fh)****Inputs:** None.**Outputs:** R0.**Variables:** R192-R223 (for Stack).**Goal:** complete the aborted Swap Phase after a Swap fail.

This routine has to be called by the User application if after an E3™ write operation the bits FEERR of FESR0 (224002h) and SWER of FESR1 (224003h) are set. After having executed the “Find Wrong Pages routine” and the “Find Wrong Bytes routine”, and after having stored in Ram the E3™ addresses and data to program again, this routine can be called through a far call:

```
CALLS 23h, 002Fh ;Complete Swap
```

This routine performs the following operations:

- perform a Sector Erase operation on the old sector;
- during the Sector Erase operation, a User routine is called to refresh an external Watchdog if necessary. [3.7 User routine for External Watchdog Refresh](#) for details.
- write the VCSS1 register (222003h) with the sector number currently mapping the E3™ data;
- write the VCSS0 register (222001h) with the number of the last completed Erase Phase on the complementary sector;

The User Application should check the Output variable of the Complete Swap routine:

Register R0 shows if the Sector Erase operation has been completed correctly (Good Code: A4h), or if has failed (Bad Code: 50h).

**3.6 E3™ RESET TO DELIVERY STATUS (230032H)****Inputs:** None.**Outputs:** R0.**Variables:** R192-R223 (for Stack).

**Goal:** erase sectors E0 and E1 and program the NV pointers so that E0 is the current sector with all the Pages mapped in block 0 and E1 is completely erased.

This routine has to be called by the User application if the E3™ NV Pointers have lost any coherence and can be no more correctly interpreted by the “Power-On routine”. This routine can be called through a far call:

```
CALLS 23h, 0032h ;E3™ Reset
```

This routine performs the following operations:

- perform a Sector Erase operation on sector E0;
- perform a Sector Erase operation on sector E1;
- program FDh in the NVCSS1 register of sector E0 (229003h);
- write 00h in the VCSS1 register (222003h): E0 is the sector currently mapping the E3™ data;
- program 00h in the NVCSS0 register of sector E0 (229001h);
- write 30h in the VCSS0 register (222001h): Erase Phase 3 has been completed on complementary sector E1;
- program EEh in the NVESP0-63 registers of sector E0 (229000h-22907Eh);
- write 00h in the VESP0-63 registers (222000h-2223F0h): all Pages are mapped in block 0 of sector E0;
- each time an E3™ write operation is performed, a User routine is called to eventually refresh an external Watchdog. [3.7 User routine for External Watchdog Refresh](#) for details.

The User Application should check the Output variable of the E3™ Reset routine:

Register R0 shows if the Sector Erase operations have been completed correctly (Good Code: A4h), or if have failed (Bad Code: 50h).

### 3.7 USER ROUTINE FOR EXTERNAL WATCHDOG REFRESH

**Inputs:** None.

**Outputs:** None.

**Variables:** None.

**Goal:** to refresh the external Watchdog during the BootRom code execution.

This routine has to be written by the User in Flash. The address where the routine starts has to be written in 000006h (1 word), while the segment where the routine is located has to be written in 000009h (1 byte).

This routine is called at least once every time that the BootRom execution performs an E3™ write operation. If the write operations has a long duration, the User routine is called with a rate

fixed by location 000008h: with an internal clock frequency of 2MHz, location 000008h fixes the number of milliseconds to wait between two calls of the User routine.

**Table 6. User routine parameters**

Location	Size	Notes
000006h	2 byte	User routine address
000008h	1 byte	ms rate at 2MHz
000009h	1 byte	User routine segment

If location 000006h is virgin (FFFFh), the User routine is not called.

The user routine is called only by the E3™ management routines (E3™ Swap Error Routines, E3™ Reset routine) in testflash revisions 2.5 and 2.6, but is also called by the E3™ initialization routine at Power on in testflash version 2.5.

To avoid modifying the User initialization, when the BootRom code calls the User routine, it does not perform the standard initializations:

- The MMU paged registers are set as shown by the following table.

**Table 7. MMU Registers Initialization**

Register	Value	Seg	Notes
DPR0 - R240	00h	0h	1st 16k-page
DPR1 - R241	89h	22h	2nd 16k-page
DPR2 - R242	8Ah	22h	3rd 16k-page
DPR3 - R243	8Bh	22h	4th 16k-page
ISR - R248	XXh	XXh	not modified
DMASR - R249	XXh	XXh	not modified
MPSR - R250	XXh	XXh	not modified
MDPR0 - R251	XXh	XXh	not modified
MDPR1 - R252	XXh	XXh	not modified

- Bit MEMSEL (bit 4) of R246 (EMR2) page 21 is not modified.
- The Register Page Pointer is set to page 21.
- Group 0 is set as the working register group.
- Data Memory is Set.

The User routine must avoid modifying the context of the BootRom routine. The following registers must not be modified when the User routine returns:

- System Stack Pointer: RR238.
- Page Pointer: R234.

- Register Pointers: RR232.
- Bit 0 of Flag Register: R231.
- Data Page Pointers DPR0-3.
- Registers of Groups 0 and 1.



## 4 E3™ FAILURE RECOVERY

### 4.1 ERASE OR WRITE ERROR: FATAL ERROR

ST guarantees 100 000 erase cycles endurance for the E3™, which corresponds to 800 000 write cycles for the most updated page (1 page contains 16 bytes). But after this period, an erase error or a write error may occur. This error is due to one or several flash cells that cannot be erased (logic level 1) or programmed (logic level 0) anymore. This is a hardware failure and the only workaround is to not use these bytes, which means that the data must be relocated. As each time a data is updated, the whole page is recopied, consequently the whole page should be remapped in order to avoid any erase/write error at the same location.

### 4.2 SWAP ERROR: NON FATAL ERROR

A swap error may occur during the E3™ product life. Till now, no swap error has been identified in any application using the Emulated E3™ of the ST9. Anyway, this error is not fatal and there are 2 ways to recover:

#### 4.2.1 Generate a reset

Generating a software reset will automatically execute the testflash, which will complete the E3™ swap operation. It will restore the E3™ content as it was before the last writing attempt, which means that the last updated data is lost.

#### 4.2.2 Call the “complete aborted swap phase” routine in testflash.

The fastest way to complete the swap operation is to call the routine “complete aborted swap phase” directly in testflash. This is done by the instruction:

```
CALLS 0x23, 0x002F ;Complete Swap
```

The “complete aborted swap phase” routine will restore the E3™ content as it was before the last write attempt, which means that the last updated data is lost. It is possible for the user to find exactly what was the last page and byte written by calling the routines “Find wrong page” and then “Find wrong byte”.

“THE PRESENT NOTE WHICH IS FOR GUIDANCE ONLY AIMS AT PROVIDING CUSTOMERS WITH INFORMATION REGARDING THEIR PRODUCTS IN ORDER FOR THEM TO SAVE TIME. AS A RESULT, STMICROELECTRONICS SHALL NOT BE HELD LIABLE FOR ANY DIRECT, INDIRECT OR CONSEQUENTIAL DAMAGES WITH RESPECT TO ANY CLAIMS ARISING FROM THE CONTENT OF SUCH A NOTE AND/OR THE USE MADE BY CUSTOMERS OF THE INFORMATION CONTAINED HEREIN IN CONNECTION WITH THEIR PRODUCTS.”

Information furnished is believed to be accurate and reliable. However, STMicroelectronics assumes no responsibility for the consequences of use of such information nor for any infringement of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of STMicroelectronics. Specifications mentioned in this publication are subject to change without notice. This publication supersedes and replaces all information previously supplied. STMicroelectronics products are not authorized for use as critical components in life support devices or systems without express written approval of STMicroelectronics.

The ST logo is a registered trademark of STMicroelectronics.

All other names are the property of their respective owners

© 2004 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia – Belgium - Brazil - Canada - China – Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

[www.st.com](http://www.st.com)